

Notice of References Cited

Application/Control No.

10/524,366

Applicant(s)/Patent Under

Reexamination

MEYER ET AL.

Examiner

PATRICIA L. HAILEY

Art Unit

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B US-2006/0009545 A1	01-2006	Frahn et al.	523/200
C	US-			
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I	US-			
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K	US-			
L	US-			
M	US-			

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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